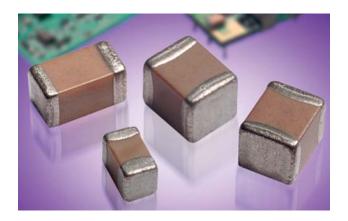
General Specifications





X7R formulations are called "temperature stable" ceramics and fall into EIA Class II materials. X7R is the most popular of these intermediate dielectric constant materials. Its temperature variation of capacitance is within $\pm 15\%$ from -55°C to +125°C. This capacitance change is non-linear.

Capacitance for X7R varies under the influence of electrical operating conditions such as voltage and frequency.

X7R dielectric chip usage covers the broad spectrum of industrial applications where known changes in capacitance due to applied voltages are acceptable.

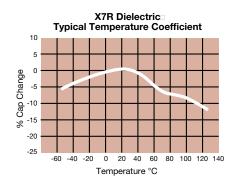
**See FLEXITERM® X7R section

RoHS

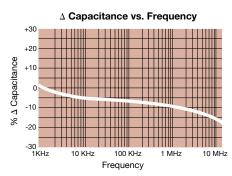
PART NUMBER (see page 2 for complete part number explanation)

0805 103 C Capacitance Voltage Dielectric Capacitance **Failure Terminations Packaging** Special 5 4 1 Code (In pF) **Tolerance** Rate Ċode T = Plated Ni 6.3V = 6 $J = \pm 5\%$ A = Not4 = 13" Reel A = Std. Product 2 Sig. Digits + and Sn 10V = Z 16V = Y $K = \pm 10\%$ Applicable 7 = Bulk Cass. Number of Zeros 7 = Gold Plated* $M = \pm 20\%$ 9 = BulkZ=FLEXITERM®** 25V = 350V = 5*≤1µF only, Contact 100V = 1contact factory for *Optional termination **Factory For** 200V = 2additional values

NOTE: Contact factory for availability of Termination and Tolerance Options for Specific Part Numbers. Contact factory for non-specified capacitance values.



500V = 7



Insulation Resistance vs Temperature

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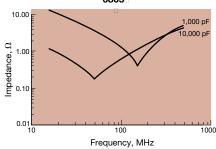
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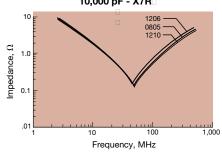
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Multiples

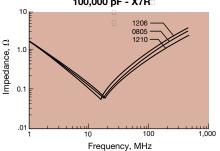
Variation of Impedance with Cap Value Impedance vs. Frequency□ 1,000 pF vs. 10,000 pF - X7R□ 0805□



Variation of Impedance with Chip Size Impedance vs. Frequency□ 10,000 pF - X7R□



Variation of Impedance with Chip Size Impedance vs. Frequency□ 100,000 pF - X7R□







Specifications and Test Methods

	ter/Test	X7R Specification Limits	Measuring Conditions				
	perature Range	-55°C to +125°C	Temperature C	ycle Chamber			
Capacitance Dissipation Factor		Within specified tolerance ≤ 2.5% for ≥ 50V DC rating ≤ 3.0% for 25V DC rating ≤ 3.5% for 25V and 16V DC rating ≤ 5.0% for ≤ 10V DC rating	Freq.: 1.0 k Voltage: 1.0				
Insulation Resistance		100,000MΩ or 1000MΩ - μ F, whichever is less	Charge device with rated voltage for 120 ± 5 secs @ room temp/humidity				
Dielectric	Strength	No breakdown or visual defects	Charge device with 300% of rated voltage f 1-5 seconds, w/charge and discharge curre limited to 50 mA (max) Note: Charge device with 150% of rated voltage for 500V devices.				
	Appearance	No defects	Deflection: 2mm				
Resistance to Flexure Stresses	Capacitance Variation	≤ ±12%	Test Time: 30 seconds				
	Dissipation Factor	Meets Initial Values (As Above)	V				
	Insulation Resistance	≥ Initial Value x 0.3	90 mm				
Solderability		≥ 95% of each terminal should be covered with fresh solder	Dip device in eutectic solder at 230 \pm 5°C for 5.0 \pm 0.5 seconds				
	Appearance	No defects, <25% leaching of either end terminal					
	Capacitance	≤ ±7.5%					
	Variation		Dip device in eutectic solder at 260°C for 60 seconds. Store at room temperature for 24 ± 2 hours before measuring electrical properties.				
Resistance to Solder Heat	Dissipation Factor	Meets Initial Values (As Above)					
	Insulation Resistance	Meets Initial Values (As Above)					
	Dielectric Strength	Meets Initial Values (As Above)					
Thermal Shock	Appearance	No visual defects	Step 1: -55°C ± 2°	30 ± 3 minutes			
	Capacitance Variation	≤ ±7.5%	Step 2: Room Temp	≤ 3 minutes			
	Dissipation Factor	Meets Initial Values (As Above)	Step 3: +125°C ± 2°	30 ± 3 minutes			
	Insulation Resistance	Meets Initial Values (As Above)	Step 4: Room Temp	≤ 3 minutes			
	Dielectric Strength	Meets Initial Values (As Above)	Repeat for 5 cycles ar 24 ± 2 hours at room				
Load Life Load Humidity	Appearance	No visual defects					
	Capacitance Variation	≤ ±12.5%	Charge device with 1.5 rated voltage (≤ 10V) in test chamber set at 125°C ± 2°C				
	Dissipation Factor	≤ Initial Value x 2.0 (See Above)	for 1000 hours (+48, -0)				
	Insulation Resistance	≥ Initial Value x 0.3 (See Above)	Remove from test chamber and stabilize at room temperature for 24 ± 2 hours before measuring.				
	Dielectric	Meets Initial Values (As Above)					
	Strength	· · · · · · · · · · · · · · · · · · ·					
	Appearance	No visual defects	Store in a test chamber set at 85° C $\pm 2^{\circ}$ C/ $85\% \pm 5\%$ relative humidity for 1000 hours (+48, -0) with rated voltage applied.				
	Capacitance Variation	≤ ±12.5%					
	Dissipation Factor	≤ Initial Value x 2.0 (See Above)	Remove from chamber and stabilize at				
	Insulation Resistance	≥ Initial Value x 0.3 (See Above)	room temperature and humidity for 24 ± 2 hours before measuring.				
	Dielectric Strength	Meets Initial Values (As Above)	24 ± 2 Hours before Measuring.				







PREFERRED SIZES ARE SHADED

Ш ш SIZE 0101* 0402 0603 0805 1206 0201 Soldering Reflow Only Reflow Only Reflow/Wave Reflow/Wave Reflow/Wave Reflow/Wave Packaging All Paper All Paper All Paper Paper/Embossed Paper/Embossed Paper/Embossed 0.40 ± 0.02 1.00 ± 0.10 (0.040 ± 0.004) 1.60 ± 0.15 (L) Length (0.126 ± 0.008) (0.016 ± 0.0008) (0.024 ± 0.001) (0.063 ± 0.006) (0.079 ± 0.008) 0.50 ± 0.10 (0.020 ± 0.004) 0.20 + 0.02 0.30 ± 0.03 0.81 ± 0.15 (W) Width (0.008 ± 0.0008) (0.011 ± 0.001) (0.032 ± 0.006) (0.049 ± 0.008) (0.063 ± 0.008) 0.20 ± 0.02 (0.008 ± 0.0008) 0.15 ± 0.05 (0.006 ± 0.002) 0.25 ± 0.15 (0.010 ± 0.006) 0.35 ± 0.15 (0.014 ± 0.006) 0.50 ± 0.25 (0.020 ± 0.010) 0.50 ± 0.25 (0.020 ± 0.010) (t) Terminal mm (in.) WVDC 10 16 25 50 10 16 25 50 16 25 50 100 200 16 25 50 100 200 16 25 50 100 200 A A A A Α 470 471 Α 1000 102 1500 3300 4700 Α 6800 M N 104 0.15 0.22 224 N 0.33 N N N N N N N N P 0.68 М М 4.7 475 106 476 WVDC 50 100 200 50 100 200 500 0101 SIZE

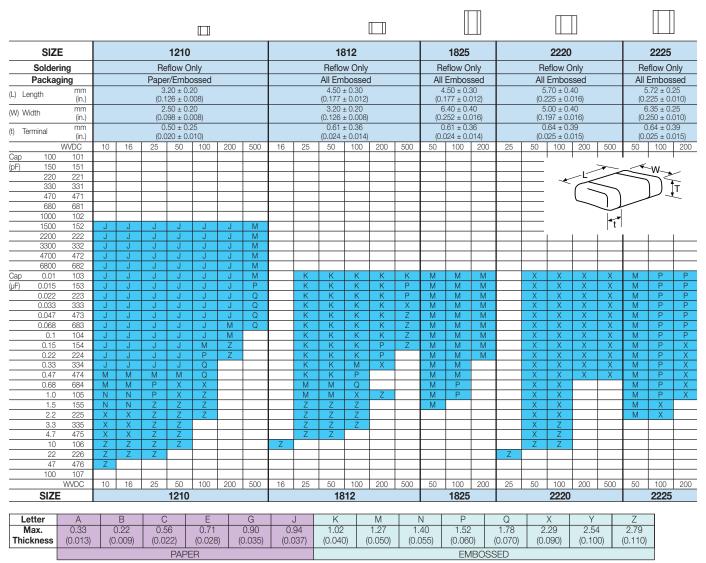
Letter	Α	В	С	Е	G	٦	K	М	N	Р	Q	Χ	Υ	Z
Max.	0.33	0.22	0.56	0.71	0.90	0.94	1.02	1.27	1.40	1.52	1.78	2.29	2.54	2.79
Thickness	(0.013)	(0.009)	(0.022)	(0.028)	(0.035)	(0.037)	(0.040)	(0.050)	(0.055)	(0.060)	(0.070)	(0.090)	(0.100)	(0.110)
	PAPER					EMBOSSED								

NOTE: Contact factory for non-specified capacitance values

*EIA 01005



PREFERRED SIZES ARE SHADED



NOTE: Contact factory for non-specified capacitance values

